Docket No. 34261-8500

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

n Application of:

Howard Ge et al.

MAR 1 4 2005

Serial No.: 10/680,960

Filed: 10/07/2003

For: PHOTORESIST COASTING PROCESS FOR

**MICROLITHOGRAPHY** 

Examiner:

Group Art Unit: 1756

March 10, 2005

Irvine, California 92614

## INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Dear Sir:

In an attempt to fully comply with the duty of disclosure set forth in 37 C.F.R. § 1.56 and in conformance with 37 C.F.R. §§ 1.97 and 1.98, applicant wishes to bring to the attention of the U.S. Patent Office the following references, which was found during the prosecution of a co-pending PCT International Patent Application:

U.S. Patent No. 5,032,217

U.S. Patent No. 2,046,596

U.S. Patent No. 5,455,062

U.S. Patent No. 5,498,449

U.S. Patent No. 6,403,500

U.S. Patent Application Publication No. 2002/0092917

European Patent Application No. EP 0 654 306

Patent Abstracts of Japan Publication No. 11-010041

KUTCHOUKOV V G ET AL.: "New photoresist coating method for 3-D structured wafers" SENSORS AND ACTUATORS A, ELSEVIER SEQUOIA S.A., LAUSANNE, CHI, vol. 85, no. 1-3, 25 August 2000 pages 377-383.

Copies of the foreign references, Kutchoukov et al. article and form PTO-A820 are attached.

The undersigned attorney hereby certifies that each item contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart international application not more than three months prior to filing this statement.

If the Examiner believes that a telephone conference would help further the prosecution of this case, he is respectfully requested to contact the undersigned attorney at the listed telephone number.

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as first class mail in an envelope addressed to: Mail Stop, Commissioner for Patent, PO Box 1450, Alexandria, VA 22313-1450 on March 10, 2005

by: Melissa Gamarra

Signature

Date of Signature: March 10, 2005

Very truly yours,

SNELL & WILMER LLP

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Irvine, CA 92614 Phone 949/253-2720

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INFORMATION DISCLOSURE CITATION					Applicant(s) Howard Ge et al.		10/680,960			
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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING		
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		2,046,596	7/7/1936	Zwiebel	·			<u></u>	_	
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,		2002/0092917	7/18/2002	Ko et al.						
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FOREIGN PATENT DOCUMENTS										
	REF	DOCUMENT NUMBER	DATE		COUNTRY		SUBCLASS	Translation YES NO		
	11-010041		19-01-1999	Patent Abstracts of Japan				<b>&gt;</b>		
		0 654 306	27-05-1994	Europe				>		
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			OTHER D	OCUMEN	TS (Including Author,	Title, Date, F	Pertinent Pages, Et	'c.)		
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EXAMINER					DATE CONSIDERED					
		al if citation considered, whether clude copy of this form with nex			Luce with MPEP Section 609; Du	raw line thro	ugh citation if not	in conform	ance and	

Docket Number (Optional)